

# 1V Compact Class-AB CMOS Log Filters

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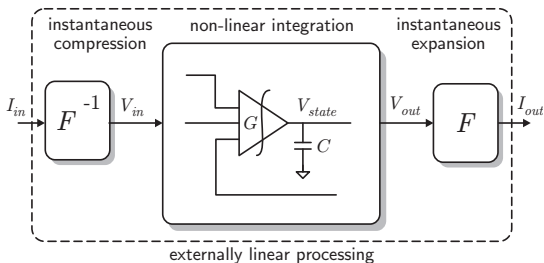
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- 1 Introduction
- 2 Basic Class-A Operation
- 3 New Class-AB Proposal
- 4 Design Example
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## Compressing filtering scenario

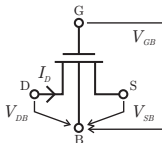


$$\text{log-domain: } F(x) = e^x$$

- ✓ Low-voltage
- ? Low-current vs dynamic range
- ? Low-area vs auxiliary circuitry

... the answer is **compact Class-AB!**

## MOS log-mapping



weak inversion:

$$V_{SB, DB} \gg \frac{V_{GB} - V_{TO}}{n}$$

forward saturation:

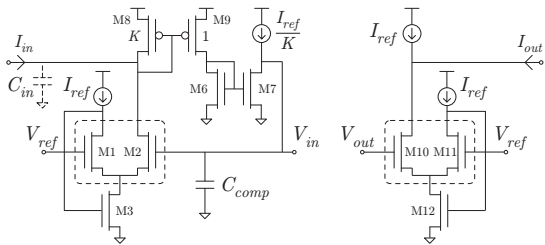
$$V_{DB} - V_{SB} \gg U_t$$

$$I_D = I_S e^{\frac{V_{GB} - V_{TO}}{n U_t}} e^{-\frac{V_{SB}}{U_t}}$$

$$I_S = 2n\beta U_t^2 \quad IC = \frac{I_D}{I_S}$$

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## Compressor and expander



boxed devices in weak inversion saturation:

$$I = F(V) = I_{ref} e^{\frac{V - V_{ref}}{nU_t}} \quad I > 0$$

Note: presented by same authors in ISCAS'00

- ✓  $V_{ref}$  used to optimize low-voltage: M3,12 do not need saturation!
- ✓  $K$  allows simple frequency compensation

$$\zeta = \frac{1}{2} \sqrt{\frac{KC_{comp}}{C_{in}}}$$

$$K \geq 2 \frac{C_{in}}{C_{comp}}$$

- ✗  $I_{ref}$  limits the full-scale due to log-mapping:

$$I_{max} \equiv \frac{I_{ref}}{2}$$

with thermal noise:

$$\Delta SNR = +3\text{dB/oct}(I_{ref})$$

... **poor** improvement!

## Integrator

- ▶ ODE in the lineal  $I$ -domain:

$$\frac{dI_{out}}{dt} = \pm \frac{1}{\tau} I_{in}$$

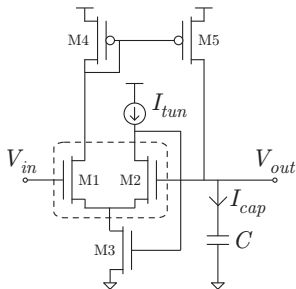
- ▶ ODE in the compressed  $V$ -domain:

$$\frac{dV_{out}}{dt} = \pm \frac{nU_t}{\tau} e^{\frac{V_{in}-V_{out}}{nU_t}}$$

- ▶ ODE in the circuit  $Q$ -domain:

$$\frac{dQ_{out}}{dt} = C \underbrace{\frac{dV_{out}}{dt}}_{I_{cap}} = \pm I_{tun} e^{\frac{V_{in}-V_{out}}{nU_t}}$$

$$\tau = \frac{nU_t C}{I_{tun}}$$



- ✓ Tunable time constant
- ✓ Single dis/charge due to log mapping ( $I_{in} > 0$ ), op ensured at filter level
- ✓ Half integrator shared
- ✗  $SNR$  issues ( $I_{tun} \geq I_{ref}$ ) cause **high-value**  $C$ !

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## Input Splitter and Compressor

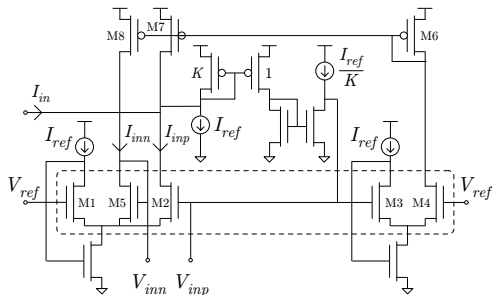
- ▶ Differential signaling:

$$I_{in} = I_{inp} - I_{inn}$$

$$I_{inp,n} > 0$$

- ▶ Constant geometric mean splitting:

$$I_{inp} I_{inn} = I_{ref}^2$$



- ✓ Same low-voltage capability as Class-A
- ✓ Full-scale  $I_{max} \leftrightarrow I_{ref}$
- ✓ **Optimization:**  $I_{ref} \downarrow$   
 $\Delta SNR \simeq +6\text{dB/oct}(I_{max})$
- current multiplier M1-M4
- $\frac{I_{ref}^2}{I_{inp}}$  feedback M6-M8
- M2 shared by TL+compressors

## Differential Integrator with CMFB (1)

- ▶ ODE in the linear  $I$ -domain for multiple-inputs:

$$\frac{dI_{out}}{dt} = \frac{1}{\tau} \sum_K \pm I_{inK} \quad (\text{even different } \tau_K)$$

- ▶ High-gain **CMFB** to ensure geometric-mean common-mode:

$$\frac{dI_{outp}}{dt} = \frac{1}{\tau} \left[ \sum_K \pm I_{inpK} - \frac{I_{outp} I_{outn}}{I_{ref}} + I_{ref} \right]$$

✓ Does not affect  $I_{out}$

✓ **CMFB overhead**

$\propto$  filter order

$\Leftrightarrow$  filter complexity

$$\frac{dI_{outn}}{dt} = \frac{1}{\tau} \left[ \sum_K \pm I_{innK} - \frac{I_{outp} I_{outn}}{I_{ref}} + I_{ref} \right]$$

## Differential Integrator with CMFB (2)

- ▶ ODE in the compressed  $V$ -domain:

$$\frac{dV_{outp}}{dt} = \frac{nU_t}{\tau} \left[ \sum_K \pm \frac{I_{inpK}}{I_{outp}} - \frac{I_{outn}}{I_{ref}} + \frac{I_{ref}}{I_{outp}} \right]$$

$$\frac{dV_{outn}}{dt} = \frac{nU_t}{\tau} \left[ \sum_K \pm \frac{I_{innK}}{I_{outn}} - \frac{I_{outp}}{I_{ref}} + \frac{I_{ref}}{I_{outn}} \right]$$

- ▶ Finally, ODE in the circuit  $Q$ -domain:

$$\frac{dQ_{outp}}{dt} = I_{tun} \left[ \sum_K \pm e^{\frac{V_{inpK} - V_{outp}}{nU_t}} - e^{\frac{V_{outn} - V_{ref}}{nU_t}} + e^{\frac{V_{ref} - V_{outp}}{nU_t}} \right]$$

**cross**  $\updownarrow$  **coupled**

$$\frac{dQ_{outn}}{dt} = I_{tun} \left[ \sum_K \pm e^{\frac{V_{innK} - V_{outn}}{nU_t}} - e^{\frac{V_{outp} - V_{ref}}{nU_t}} + e^{\frac{V_{ref} - V_{outn}}{nU_t}} \right]$$

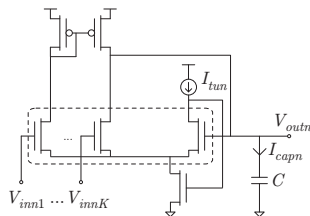
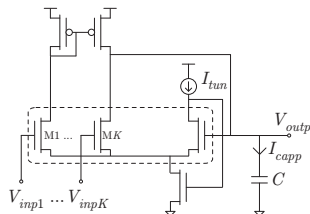


## Differential Integrator with CMFB (and 3)

### ► Realization:

$$\frac{dQ_{outp}}{dt} = I_{tun} \left[ \sum_K \pm e \frac{V_{inpk} - V_{outp}}{nUt} \right. \\ \left. - e \frac{V_{outn} - V_{ref}}{nUt} + e \frac{V_{ref} - V_{outp}}{nUt} \right]$$

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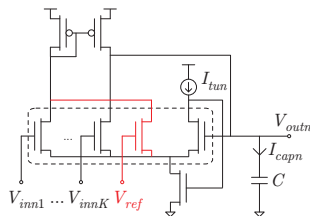
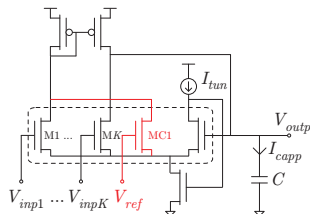
- ✓ Low-voltage capability
- ✓ Most CMFB shared by 1...K
- ✓ Half CMFB shared by all C's
- ✓  $I_{ref} \downarrow$  allows  $I_{tun} \downarrow$ , so **downscaling C** (Si area)

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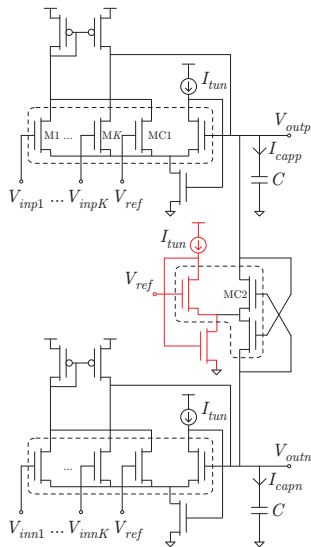
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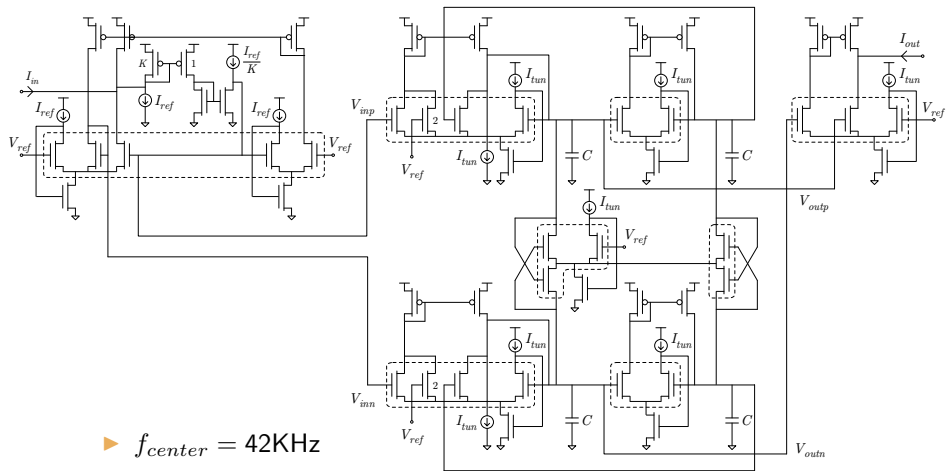






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## Second-Order Band-Pass Log-Filter



▶  $f_{center} = 42\text{KHz}$

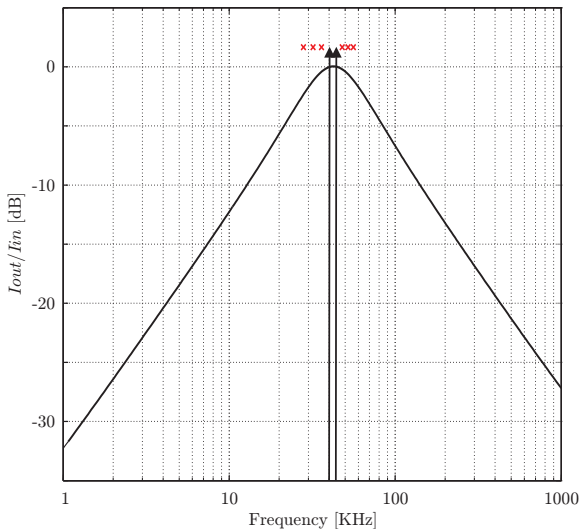
▶  $Q = 1$

## Class-A versus New Class-AB

- ▶ 0.35 $\mu\text{m}$  CMOS technology
- ▶ Designed for the **same full-scale**
- ▶ *IMD* analysis through periodic steady-state (PSS) simulations:

$$f_{in1} = 40\text{KHz}$$

$$f_{in2} = 44\text{KHz}$$

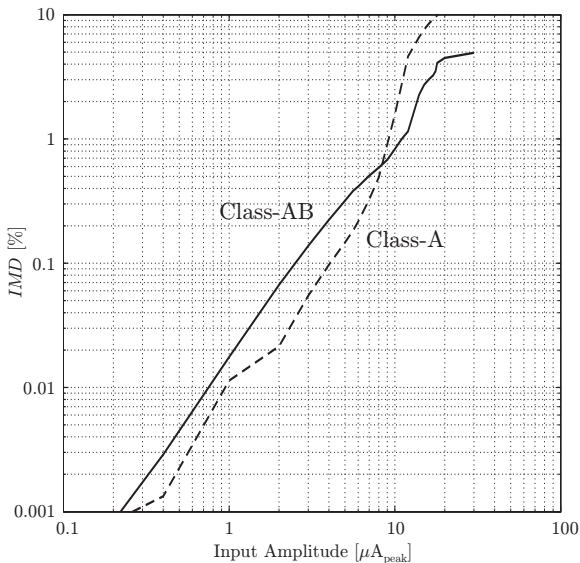


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## Overall Results

	Class-A	Class-AB	Units
Supply voltage		1	V
$V_{TON} +  V_{TOP} $		1.2	V
$V_{ref}$		0.5	V
$I_{ref}$ (and $I_{tun}$ )	10	<b>2.5</b>	$\mu A$
$C$	1000	<b>250</b>	pF
Boxed-MOSFET ratios	$50 \times \frac{40}{1.5}$	$21 \times \frac{40}{1.5}$	$\frac{\mu m}{\mu m}$
Signal full-scale		$\sim 10$	$\mu A_p$
$IMD$ @ half full-scale	0.15	0.3	%
$DR$ (10KHz-100KHz)	68	$> 68$	dB
Quiescent power	150	<b>85</b>	$\mu W$
Total capacitance	2000	<b>1000</b>	pF
Total boxed-MOS area	0.033	0.037	$mm^2$

✓ -40% overall power

✓ -50% capacitance area

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## Conclusions

- ▶ Very **low-voltage Class-AB** CMOS log filters
- ▶ **Complete** set of basic building blocks:  
splitting, compression, expansion, integration and CMFB
- ▶ Quiescent **low-power** consumption
- ▶ **Compact** area with reduced circuit overhead
- ▶ 0.35 $\mu\text{m}$  CMOS Class-A/AB comparative **example**